Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,028	YI ET AL.	
Examiner	Art Unit	
A Devter Tughang	3729	

SEARCHED					
Class	Subclass	Date	Examiner		
29	603.13 603.14 603.08	3/3/2006	ADT		
360	322 324.2				
	324.4				
427	523				
	525 529				
	530	→	1		
428	811	3/6/2006	ADT		
	811.1				
204	192.1				
	192.5				
	192.2				
148	101				
438	694	V			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consulted C. Renner, Primary - Class 360	3/3/2006	ADT
Text Search: IEEE Xplore Database	3/3/2006	ADT